Resolving the Chemically Discrete Structure of Synthetic Borophene Polymorphs

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ABSTRACT: Atomically thin two-dimensional (2D) materials exhibit superlative properties dictated by their intralayer atomic structure, which is typically derived from a limited number of thermodynamically stable bulk layered crystals (e.g., graphene from graphite). The growth of entirely synthetic 2D crystals, those with no corresponding bulk allotrope, would circumvent this dependence upon bulk thermodynamics and substantially expand the phase space available for structure—property engineering of 2D materials. However, it remains unclear if synthetic 2D materials can exist as structurally and chemically distinct layers anchored by van der Waals (vdW) forces, as opposed to strongly bound adlayers. Here, we show that atomically thin sheets of boron (i.e., borophene) grown on the Ag(111) surface exhibit a vdW-like structure without a corresponding bulk allotrope. Using X-ray standing wave-excited X-ray photoelectron spectroscopy, the positions of boron in multiple chemical states are resolved with sub-Å spatial resolution, revealing that the borophene forms a single planar layer that is 2.4 Å above the unreconstructed Ag surface. Moreover, our results reveal that multiple borophene phases exhibit these characteristics, denoting a unique form of polymorphism consistent with recent predictions. This observation of synthetic borophene as chemically discrete from the growth substrate suggests that it is possible to engineer a much wider variety of 2D materials than those accessible through bulk layered crystal structures.

KEYWORDS: X-ray standing wave, X-ray photoelectron spectroscopy, boron, borophene, two-dimensional materials
underlying Ag(111) substrate by a gap of 2.4 Å with no evident B–Ag primary bonding site. This work thus experimentally demonstrates that borophene is a synthetic, elemental 2D material with no known bulk analogue.

Two structural phases of borophene have been observed experimentally via scanning tunneling microscopy (STM) and low-energy electron diffraction (LEED): a primitive rectangular phase [R phase; (Figure 1d)] and a diamond phase [D phase; (Figure 1e)],\(^3\)\(^4\) which are expected to match the computationally predicted \(\beta_{12}\) and \(\chi_3\) structures, respectively.\(^3\)\(^4\)\(^15\)\(^23\)\(^24\) The phase of borophene is determined by the boron deposition rate and the Ag(111) substrate temperature during growth.\(^3\)\(^4\)

Samples of both principally R phase and D phase were grown at 300 and 400 °C, respectively, in a dedicated preparation chamber attached to the main X-ray analysis chamber at beamline I09 at the Diamond Light Source under ultrahigh vacuum (UHV, \(P < 5 \times 10^{-10}\) mbar). Boron was deposited at 0.002 Å/s for 20 min to a coverage of nominally 0.3 \(\text{B/Å}^2\), where one complete monolayer of borophene corresponds to 0.35 \(\text{B/Å}^2\) and 0.29 \(\text{B/Å}^2\) in the \(\beta_{12}\) and \(\chi_3\) models, respectively, as shown in Figure 1b,c. See Supporting Information for addition details on sample preparation.

LEED patterns were acquired to verify the 2D crystal phases present after boron deposition. The LEED pattern for the 300 °C growth (Figure 1g) is consistent with the R phase\(^3\)\(^1\)\(^9\)\(^26\) and the \(\beta_{12}\) reciprocal lattice vectors (but rotated 30° with respect to the Ag spots). Growth at 400 °C results in a LEED pattern (Figure 1h) consistent with predominantly D phase,\(^3\)\(^4\)\(^21\) which can be explained by a combination of the reciprocal lattice vectors of both the \(\chi_3\) and \(\beta_{12}\) models. See Figure S1 in Supporting Information for further discussion of the LEED patterns. As will be shown later by XPS, the 300 °C borophene is \(\sim\)90% R phase and the 400 °C borophene is \(\sim\)90% D phase.

Comparative STM imaging (Figure 1d,e) was performed in a separate UHV system on samples grown under similar conditions (at a growth temperature of \(\sim\)400 °C), resulting in the presence of both R and D phase islands. The STM images were acquired by an Omicron-Scienta Cryo-SPM microscope at 2.5 K in constant-current topography mode, using an electrochemically etched tungsten tip.

To analyze the character of the bonds at the B/Ag(111) interface, we probed the chemical identity of the R and D phases \textit{in situ} using XPS and XSW at the Diamond Light Source I09 beamline, which can provide both soft (100–2100 eV) and hard X-rays (2.1–20 keV) at the same spot on the sample from two separate undulators. Soft X-rays were used a defocused beam size of 300 \(\times\) 300 \(\mu\text{m}^2\). Hard X-rays were focused down to 40% of the original 300 \(\times\) 300 \(\mu\text{m}^2\) beam size. XSW measurements were acquired using hard X-rays in a back-reflection geometry (i.e., \(\theta_B \lesssim 90°\)) to maximize the B 1s yield and minimize the effect of Ag(111) mosaicity.\(^3\)\(^\text{A}^\text{N}\) An incident beam energy of \(E = 2.629\) keV was selected by tuning the first harmonic of the 109 undulator and the Si(111) double-crystal monochromator. At this energy, the incident beam fwhm bandwidth was \(E = 0.36\) eV. We measured O 1s, Ag 3d, C 1s, B 1s, and survey XPS spectra at variable soft X-ray energies, the fwhm bandwidth was \(E = 90\) meV at 500 eV. No evidence of other elements (namely, oxygen or carbon) was observed in the survey scans (Figure S2), verifying a chemically pure borophene sample. Borophene samples were found to tolerate X-ray irradiation with no apparent degradation (i.e., no change in B 1s signal) despite multihour X-ray exposures.

Figure 2 shows high-resolution B 1s and Ag 3d core-level spectra for borophene grown at 300 and 400 °C. In both samples, the B 1s spectra (Figure 2a) are composed of a common set of chemically shifted components and are considerably narrower than multilayer boron B 1s spectra (Figure S3). This observation suggests that the boron atoms in borophene occupy discrete local bonding environments. In bulk-derived 2D crystals, observations of multiple binding energies in the core-level spectra of the 2D material are accompanied by vertical undulations in the long-range structure\(^29\)\(^\text{A}^\text{N}\)\(^2\)\(^6\)\(^\text{A}^\text{N}\)\(^2\)\(^8\)\^ and deviations from intrinsic material properties.\(^29\)\(^\text{A}^\text{N}\)\(^3\)\(^0\)\^ These binding energy shifts are therefore attributed to disparate atomic interaction strength with the underlying substrate. In the case of borophene, the B 1s spectra can be fit with five individual components, which we instead attribute
to different B−B coordination numbers present in the two principal borophene phases: three for the R phase (R4,5,6, i.e., 4-fold, 5-fold, and 6-fold coordinations) and two for the D phase (D4,5, i.e., 4-fold and 5-fold coordinations), following the trend observed in graphene of higher binding energy corresponding to higher coordination. The relative integrated peak intensity of these components reflects the proportions of boron atoms in their corresponding chemical environment. The intensity ratios of the components of the B 1s spectra (Figure 2a) are consistent with the predicted ratios of 4-fold, 5-fold, and 6-fold coordinated boron atoms in the β12 and χ3 borophene crystal structures. In both samples, the Ag 3d spectra (Figure 2b) are indistinguishable from that of clean Ag(111), apart from mild attenuation due to the boron overlayer, which indicates the borophene samples are free of B−Ag compounds.

To investigate whether any chemical species possess a varying depth profile, we collected XPS data at 16 distinct photoemission angles. Selecting a series of detector emission angles between 4° and 56° varied the effective probing depth (Λeff) for B 1s (Figure S4) and Ag 3d5/2 photoelectrons by several angstroms. The relative intensity of the components of the B 1s and Ag 3d5/2 spectra shows no dependence on observed emission angle, indicating that all boron species are co-located and that the Ag(111) surface is bulk-like.

Although high-resolution XPS provides strong evidence of chemical coordination and co-location of boron species near the Ag(111) surface, precise structural determination requires spatially resolved methods. The XSW technique enhances XPS with high spatial resolution by modulating the photoelectron yield with an X-ray standing wave formed by the interference between the incident and reflected X-ray beams at the Bragg condition (Figure 3a).

The standing wave period is equal to the substrate Bragg diffraction plane d-spacing. Scanning the incident X-ray energy, E, through the Bragg condition causes the reflectivity, R(E), to approach unity over an eV-wide X-ray Bragg reflection and the XSW phase, ϕ(E), to shift by π-radians. Chemically specific structural information is acquired by monitoring changes in XPS intensity as the standing-wave shifts from being out-of-phase with the diffraction planes to being in-phase. The resulting XPS modulation can be analyzed to find the substrate lattice location of various atomic species both above and below the crystal surface. Such measurements have previously proven to be effective in determining the chemically precise structure of 2D material interfaces. Here, we use XSW-enhanced XPS to extract ensemble-averaged vertical positions of the surface silver and the chemically distinct boron species for both R and D phase borophene.
Depending on the precise atomic distribution the photoelectron yield from a selected chemical species (s):

\[ Y_s(E) = 1 + R(E) + 2\sqrt{R(E)}f_s \cos(\phi(E) - 2\pi P_s) \]  

(1)
gives a distinct modulation versus energy that is parametrized by the Fourier amplitude (or coherent fraction, \( f_s \)) and phase (or coherent position, \( P_s \)) of the distribution profile.  

21,22 Roughly speaking the coherent position is a normalized measurement of the atomic average position \( \bar{x}_s \) modulo the 2.359 Å d-spacing of the Ag(111) diffraction plane. The coherent fraction describes the atomic distribution width normal to the d-spacing planes.  

35 For example, a random distribution of atoms would produce \( f_s = 0 \), and \( f_s = 1 \) indicates all atoms are precisely located at \( P_s \). The Ag 3d45/2 XSW-XPS yield results in \( f_{Ag} = 1 \) and \( P_{Ag} \) for all samples, indicating that all silver atoms within the ~10 Å sampling depth are unaffected by the presence of boron. In contrast to the nearly random B 1s XSW-XPS distribution (\( f > 0.2 \)) for ~3 layers of boron deposited at 20 °C (Figure S6), the total B 1s XSW yield fit of both 300 and 400 °C borophene showed \( f_s > 0.9 \) and \( P_s = 0 \) corresponding to a narrow single-layer boron distribution (Gaussian width \( \sigma_s = 0.15 \) Å) positioned at 2.4 Å above the topmost Ag(111) atomic planes. Critically, this measurement indicates that, independent of the specific phase or B–Ag coordination, all boron atoms in borophene have strong in-plane bonds stabilized by comparatively weak interactions with the Ag(111) surface. In this context, weak interaction is defined by the lack of resolvable primary B–Ag bonding, thus indicating that the borophene layer is chemically discrete from the underlying substrate. The 2.4 Å vertical separation of borophene from the substrate is comparable to boron atoms in hBN (2.17 Å for chemisorbed boron30 and 3.26–3.40 Å for physisorbed boron31,32) which are inflamed by repulsive interactions between nitrogen atoms and metal substrates.  

The \( f_s \) and \( P_s \) values measured for borophene on Ag(111) are highly consistent with the DFT calculated values30,15,30,31,32 apart from a slightly larger-than-expected distribution width (\( \sigma_s = 0.1 \) Å expected for thermal disorder) that may be due to the very minor presence of boron clusters uncorrelated with the Ag(111) lattice (see Supporting Information for additional analysis). The relatively small calculated adhesive potential of the \( \beta_{12} \) structure (175 meV/atom)30 supports our observation that the interface is free of primary B–Ag bonds. This result shows that both R and D phase borophenes are essentially planar boron polymorphs stabilized by Ag(111). Although the substrate is expected to influence the growth and properties of the borophene sheet, recent reports of metallic characteristics35 and Dirac Fermions25,38 in borophene suggest that the electronic structure of borophene is affected by charge donation and structural perturbations of the borophene lattice from the substrate. The weak degree of B–Ag hybridization observed in these studies is consistent with our results, although further study is necessary in order to understand deviations between these measurements and the electronic structure of freestanding borophene.39  

Coordination-specific structural information can also be extracted from the XSW data using the peak-fits obtained from high-resolution B 1s XPS (detailed fitting procedures given in the Supporting Information). A S-component fit of the R phase and D phase to the 300 °C (Figure 3b) and 400 °C (Figure 3c) XSW-XPS data shows nearly identical photoelectron yields \( Y_s(E) \) for all components. Despite the distinct in-plane registry predicted between the surface silver atoms and the boron atoms in the \( \beta_{12} \) and \( \chi_s \) structures, the model fitting results (Table 1) reveal that all chemically distinct species of borophene are highly planar (\( f > 0.8 \)); Gaussian width \( \sigma_s < 0.3 \) Å with essentially the same 2.4 Å spacing above the terminal plane of Ag(111) atoms (0.0 < \( P < 0.1 \)). These results are depicted schematically in Figure 3d,e for the 300 and 400 °C borophene samples relative to the \( \beta_{12} \) and \( \chi_s \) structures, respectively. Thus, borophene appears free of major site-specific vertical displacements (\( \Delta \bar{z} \approx 0.1 \) Å), in contrast to those expected for intrinsically buckled synthetic 2D materials (e.g., 0.7 Å for silicene35 and 0.8 Å for a buckled triangular borophene lattice). Additionally, in epitaxial hBN systems ~0.6 eV B 1s core-level shifts are accompanied by corrugations of 0.6 Å on Cu(111)30 and 1.5 Å on Ir(111),45 whereas for borophene comparable B 1s shifts show no accompanying vertical displacement. Statistically significant vertical displacements (\( \Delta \bar{z} \approx 0.1 \) Å) were only for boron species with a corresponding binding energy shift of ~2.0 eV (Table S1). Thus, confirming that distinct boron atomic coordination induces the core-level shifts in the borophene B 1s components. Thus, a planar structure with slight distortions induced by substrate interactions (e.g., variable adsorption sites, Moiré pattern, and/or strain) provides the most reasonable explanation for these observations. The lack of resolvable spectroscopic signatures for chemical Ag–B interaction in XPS in turn suggests that this subtle corrugation results from noncovalent interaction with the substrate, although determining the exact nature of this interaction likely requires a combination of theory and laterally resolved chemical information. Notably, the observed maximum displacements for both phases are comparable to the predicted values for boron on Ag,10,15 which suggests that this slight buckling

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<th>300 °C borophene</th>
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<td>( B% )</td>
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<tr>
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<td>0.8(1)</td>
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\(^{a}\)B heights based on the DFT \( \beta_{12} \) (R) and \( \chi_s \) (D) structural models for borophene illustrated in Figure 1b,c acquired via private communication with Boris Yakobson.10,15 \(^{b}\)Values calculated using Ag(111) d-spacing = 2.359 Å. *Values held at fixed relative B% during fitting. Bold indicates majority phase.
relative to the planar freestanding case is expected due to substrate interactions.

Based on the boron 2D lattice determination by LEED, the coordination by XPS, and height by XSW, the R and D phases observed in STM\(^3,4\) are confirmed to be distinct in-plane vacancy configurations as predicted computationally for the β\(_1\) and \(\chi_1\) phases.\(^{8,10,15}\) This conclusion implies that borophene exhibits a unique 2D, vacancy-mediated form of structural degeneracy that is reminiscent of the complexity observed in 3D boron allotropes. This polymorphism within the borophene family further suggests that the properties of borophene and its derivatives can be systematically modified based on substrate interactions, strain, and other parameters. Overall, these results demonstrate that materials without layered bulk allotropes can be induced to form highly planar structures at the 2D limit stabilized by comparatively weak interactions with metal substrates, thereby establishing a new class of synthetic 2D materials.

**ASSOCIATED CONTENT**

Supporting Information
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Additional experimental details (PDF)

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**Notes**

The authors declare no competing financial interest.

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